

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	66	(non-volatile adj memory) and (data adj queery or DQ) and (test testing tester tested) and ((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/07 09:49
L2	38	(non-volatile adj memory) and (data adj queery or DQ) and (test testing tester tested) and ((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) and (repair replace)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/07 09:46
L3	62	((memory near2 (module unit assembly board card)) with substrate) and ((repaired repairing repairable recondition restore restored restoring refurbish\$ repair) same (fail failure failing failed error erroneous bad)) and non\$1volatile	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/07 09:46
L4	473	714/710.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/07 09:47
L5	297	714/710.ccls. and (repair replace)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/07 09:47
L6	4	(non-volatile adj memory) and (data adj queery or DQ) and (test testing tester tested) and ((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) and l4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/07 09:49
S1	52350	non-volatile adj memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 19:58
S2	10302	data adj queery or DQ	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 11:27

EAST Search History

S3	340	(non-volatile adj memory) and (data adj query or DQ)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 14:23
S4	50	("6076177" "4992849" "4992850" RE36325 "5266912" "5400003" "5612657" "6249052" "6002178" "5241266" "5424652" "5457400" "5483174" "5483175" "5807762" "5825195" "5959310" "6087676" "5450576" "5659748" "4499581" "5796746" "5812472" "5912852" "5914902" "5995424" "6182253" "5862146" "6304499" "5798961" "5423050" "5745501" "5953690" "6691055" "5875136" "6119049" "4414669" "4841434" "5805606" "5249450" "5336649" "5342807" "5359547" "5652754" "5727000" "5808919" "5954827" "6049896" "6133745" "6415397").pn.	US-PGPUB; USPAT	OR	ON	2004/02/24 11:31
S5	8	((non-volatile adj memory) and (data adj query or DQ)) and (("6076177" "4992849" "4992850" RE36325 "5266912" "5400003" "5612657" "6249052" "6002178" "5241266" "5424652" "5457400" "5483174" "5483175" "5807762" "5825195" "5959310" "6087676" "5450576" "5659748" "4499581" "5796746" "5812472" "5912852" "5914902" "5995424" "6182253" "5862146" "6304499" "5798961" "5423050" "5745501" "5953690" "6691055" "5875136" "6119049" "4414669" "4841434" "5805606" "5249450" "5336649" "5342807" "5359547" "5652754" "5727000" "5808919" "5954827" "6049896" "6133745" "6415397").pn.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 11:33

EAST Search History

S6	8	((non-volatile adj memory) and (data adj query or DQ)) and ((("6076177" "4992849" "4992850" RE36325 "5266912" "5400003" "5612657" "6249052" "6002178" "5241266" "5424652" "5457400" "5483174" "5483175" "5807762" "5825195" "5959310" "6087676" "5450576" "5659748" "4499581" "5796746" "5812472" "5912852" "5914902" "5995424" "6182253" "5862146" "6304499" "5798961" "5423050" "5745501" "5953690" "6691055" "5875136" "6119049" "4414669" "4841434" "5805606" "5249450" "5336649" "5342807" "5359547" "5652754" "5727000" "5808919" "5954827" "6049896" "6133745" "6415397").pn.) and (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 14:23
S7	161	(non-volatile adj memory) and (data adj query or DQ) and (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 14:23
S8	113	(non-volatile adj memory) and (data adj query or DQ) and (test testing tester tested) and (fail failure defect defective error failed failing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 14:24
S9	46	(non-volatile adj memory) and (data adj query or DQ) and (test testing tester tested) and ((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/07 09:46
S10	1218	(test testing tester tested) and (((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) same non-volatile)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 16:04
S11	614	(test testing tester tested) and (((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) same non-volatile) and memory.ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 16:05

EAST Search History

S12	154	(test testing tester tested).ab. and (((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) same non-volatile) and memory.ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/01 17:12
S13	56	(test testing tester tested).ab. and (((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) same non-volatile) and memory.ab. and (EPROM EEPRPM ferro-electric flash)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 16:33
S14	32627	address near2 counter	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:09
S15	11795	(address near2 counter).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:09
S16	34126	(address near2 (generate count counted counting generated generating generation generator counter)).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:12
S17	749	((address near2 (generate count counted counting generated generating generation generator counter)) and offset).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:15
S18	263	((address near2 (generate count counted counting generated generating generation generator counter)) and offset).ab. and (select selection selector mux multiplex\$\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:22
S19	34	((address near2 (generate count counted counting generated generating generation generator counter)) and (off\$1set near2 register)).ab. and (select selection selector mux multiplex\$\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 15:38
S20	2	"6130442".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/01 17:22

EAST Search History

S21	13	(US-6418066-\$ or US-6130442-\$ or US-6330693-\$ or US-6115828-\$ or US-6141768-\$ or US-6256756-\$ or US-6467054-\$ or US-6345367-\$ or US-6274395-\$ or US-6477672-\$ or US-6567941-\$ or US-6651202-\$). did. or (US-20020080383-\$).did.	US-PGPUB; USPAT	OR	OFF	2004/03/05 13:16
S26	72660	memory adj (module card)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 14:31
S27	1882	(memory adj (module card)) with substrate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 14:44
S28	216	((memory adj (module card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 16:55
S29	220	((memory adj (module board card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 15:00
S30	220	((memory adj (module assembly board card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 15:00
S31	243	((memory near2 (module assembly board card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 15:01
S32	339	((memory near2 (module unit assembly board card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 18:23
S33	83	((memory near2 (module unit assembly board card)) with substrate) and ((repaired repairing repairable recondition restore restored restoring refurbish\$ repair) same (fail failure failing failed error erroneous bad))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 18:24

EAST Search History

S34	43	((memory near2 (module unit assembly board card)) with substrate) and ((repaired repairing repairable recondition restore restored restoring refurbish\$ repair) same (fail failure failing failed error erroneous bad)) and non\$1volatile	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/07 09:46
S35	17	(US-20050007857-\$ or US-20020080383-\$).did. or (US-6130442-\$ or US-6256756-\$ or US-6141238-\$ or US-6418066-\$ or US-6873555-\$ or US-6467054-\$ or US-6141768-\$ or US-6330693-\$ or US-6651202-\$ or US-6477672-\$ or US-6467056-\$ or US-6345367-\$ or US-6115828-\$ or US-6567941-\$ or US-6274395-\$).did.	US-PGPUB; USPAT	OR	ON	2005/04/27 20:36
S36	3	S35 and ferroelectric	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 20:37
S37	3	S35 and ferro\$	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 20:39
S38	2	"6058055".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 20:39
S39	131	((memory adj (module card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair) and parallel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 17:01
S40	1047	discrete adj memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 17:01
S41	652	discrete adj memory	USPAT	OR	ON	2005/09/15 17:01
S42	3916	DIMM	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 19:58

EAST Search History

S43	647	DIMM.ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 19:59
S44	21	DIMM.ab. and "714"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 19:59
S45	2388	((memory near2 (module unit assembly board card)) DIMM SIMM) and ((repaired repairing repairable recondition restore restored restoring refurbish\$ repair) same (fail failure failing failed error erroneous bad)) and non\$1volatile	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 20:15
S46	518	S45 and (identify locate location identity) near4 (fail failure failing failed error erroneous bad)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 20:18
S47	80	S46 and (store with (fail failure failing failed error erroneous bad) with (element device part module))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 20:20
S48	107	S46 and (store with (fail failure failing failed error erroneous bad) with (element device part chip ic module))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:39
S49	10	US-5331188-\$.DID. OR US-5963463-\$.DID. OR US-5991215-\$.DID. OR US-5995409-\$.DID. OR US-5996096-\$.DID.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:46
S50	456	714/710.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/07 09:47
S51	166	714/710.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 22:01

EAST Search History

S52	31	714/41.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:48
S53	48	714/710.ccor. and dram	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:49
S54	2	714/710.ccor. and DIMM	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:49
S55	1	714/710.ccor. and SIMM	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:48

Application
Number

SEARCH

IDS Flag Clearance for Application 09548826



Content	Mailroom Date	Entry Number	IDS Review	Reviewer
M844	04-13-2000	6	<input checked="" type="checkbox"/>	06-14-2001 11:56:26 EXPO- CONV
M844	02-22-2001	8	<input checked="" type="checkbox"/>	06-24-2001 18:12:48 EXPO- CONV
M844	06-14-2004	15	<input checked="" type="checkbox"/>	12-11-2004 17:35:30 parmfield

UPDATE